

<b>Notice of References Cited</b>		Application/Control No. 10/552,529	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner ADAM A. ARCIERO	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,609,975 A	03-1997	Hasegawa et al.	429/217
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2002-100357 A	04-2002	Japan	MANABU et al.	
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	IPDL PAJ JPO Machine Translation for JP 2002-100357 A (04-2002)	
V		
W		
X		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.